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(54) ELECTRON SOURCE, X-RAY SOURCE AND DEVICE USING THE X-RAY SOURCE

(71) Applicant: NUCTECH COMPANY LIMITED,

Beijing (CN)

(72)Inventors: Huaping Tang, Beijing (CN); Zhiqiang

Chen, Beijing (CN); Yuanjing Li, Beijing (CN); Yonggang Wang, Beijing (CN); Zhanfeng Qin, Beijing (CN)

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(57)ABSTRACT

The present disclosure is directed to an electron source and an X-ray source using the same. The electron source of the present invention comprises: at least two electron emission zones, each of which comprises a plurality of micro electron emission units, wherein the micro electron emission unit comprises: a base layer, an insulating layer on the base layer, a grid layer on the insulating layer, an opening in the grid layer, and an electron emitter that is fixed at the base layer and corresponds to a position of the opening, wherein the micro electron emission units in the same electron emission zone are electrically connected and simultaneously emit electrons or do not emit electrons at the same time, and wherein different electron emission zones are electrically partitioned.

